Hitachi Anisotropic Conductive Film ANISOLM®

AC-7206U-18

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R & D Dept. Goshomiya Works Hitachi Chemical Co., Ltd. . Standard Specification, Bonding and Storage Conditions, Repairability, and Characteristics

. Standard Specification, Bonding and Storage Conditions, Repairability, and Characteristics										
		Item		1	Unit		AC-7206U		206U	Remark
	Small		Line		μm	pcs	25			
	conne circui		Spacir	Resolution	μm	/mm	25		20	
cifica	Thickness				μm		18		8	
spe	Width					nm	1.2,1.5,1.8,2.0,2.5		8,2.0,2.5	
dard	Length					m	50		0	
Stan	Color				-		Transparent(gray)		ent(gray)	
	Core				mm		18.5		.5	
	ary 1g	Temperature					80 ± 10		: 10	ANISOLM's ultimate temperature
tions	Temporary bonding	Pressure			MPa		1		-	
ndi	Ter bo		Time		s		5		i	
Bonding conditions	Final bonding		Temp	erature			180 ± 10)	190 ± 10	ANISOLM's ultimate temperature
ondi		Pressure		MPa		3		}		
B		Time			S	15		10		
tions	Shelf life	Packed			6 months after date of manufacture when stored at -10 to 5					
e cond		Unpacked			-	1 month at 25 or below and 70%RH or below.				
Storage conditions	SI	Pre-bonded			-	2 months at -10 to 5 .1 month at 25 or below and 70%RH or below.		or below		
	Repairability					-	Repairable			By acetone or toluene
	Connection resistance						1			ITO glass / TCP; bonding width, 1.5mm
	Insulation resistance						1012		12	Space 25 µ m; bonding width, 2.5mm
cs	Peel strength(20)					N/m	1.2		2	ITO glass / TCP hot-bonded
rist	Tack strength(20)					N/m	0.08)8	ITO glass / TCP cold-bonded
acte	Separator peeling strength				gf/2	.5mm	1.5		5	ITO glass
Characteristics	O	Operating Temperature				-40 to 100		100	Under no stress	
		range Current Voltage		A /1	mm²	50 or below		below		
					V	50 or below		below		

Notes:

Current measured: 1mA. Includes the circuit resistances of the FPC and ITO glass.

The values given above represent typical measurements, not guaranteed ones.

¹⁾Take ANISOLM out of the refrigerator or other storage without taking it out of its hermetic containers. Leave the ANISOLM in the containers at room temperature for about an hour. Then make sure that it does not risk condensation before using it.

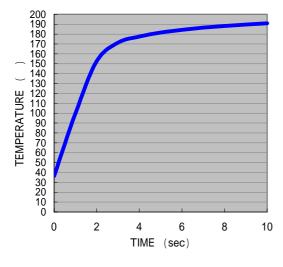
²⁾Connection resistance: The table indicates a half of the resistance between neighboring circuits.

³⁾Tack strength: Pre-bond an ANISOLM sample to an ITO glass, peel its separator off, then tack s FPC to it at room temperature. Then measure the tack strength of this sample.

⁴⁾Operating range: As per reliability tests using Hitachi's test pieces.(This range varies according to the material used and external stress applied. Check the reliability of specific pieces.)

2. Precautions in Bonding

2.1. Connection time and ANISOLM temperature(Typical)

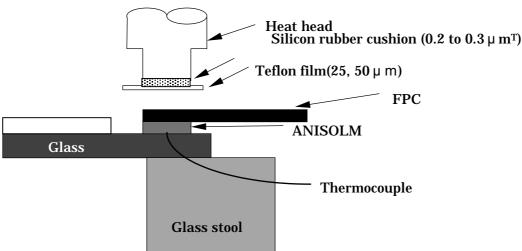


Head temperature: 295 Backup temperature: 40

TCP: Pl, 75 μ m; Cu, 18 μ m; Au plating

Glass board: 1.1mm^t

Ratio of temperature reached 5 seconds later: 90% or more of the ultimate temperature()



2.3. Heat/Pressure Head

- (1) Adjust carefully the eveness and parallelism of the heating head to keep the equal pressure.
- (2) Use a head slightly wider than the ANISOLM piece to be connected.
 -Example: ANISOLM width, 2.5mm head width, 3.0mm
- (3) Tip the head with a thin and hard cushion, not a soft and thick one. Silicon rubber(about 0.2 mm thick with a hardness of 70 degrees or above) may be used for example.

 The use of too soft a cushion or excessive pressure in connection will drive adhesive in the space toward the end, resulting in insufficient adhesion. Be particularly careful when the

2.4. Misalignment of Opposite Circuits

space is wider than the circuits.

- (1) Align opposite circuits well. Do not let them get misaligned.
- (2) In designing TABs (FPCs), allow for the misalignment of opposite circuits due to their expansion during connection.
- (3) Keep the circuit misalignment at or less than the circuit width.

3. Connection Reliability

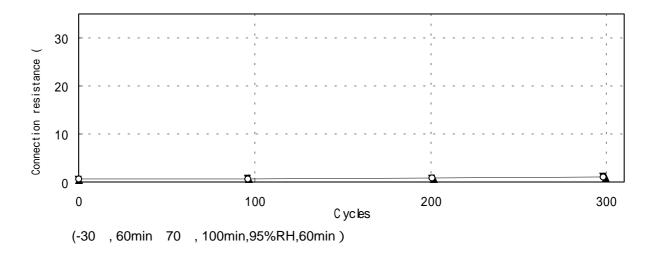
-Connection circuits

TCP: Pl, 75 μ m; Cu, 18 μ m; Sn plating; pitch, 50 μ m

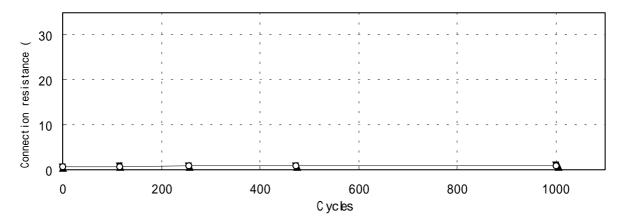
Glass: ITO sputter; 15 / ;electrodes all over

-Bonding conditions; 170 - 3MPa - 15s; ANISOLM width 1.5mm

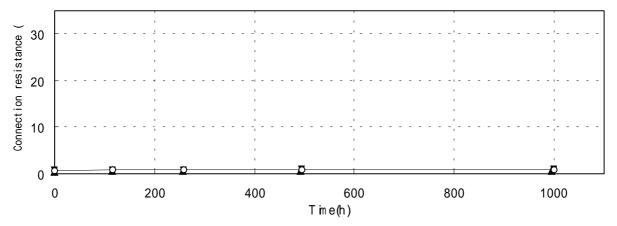
3.1. Changes in connection resistance in a moisture absorption and freeze test



3.2. Changes in connection resistance in a thermal shock test $(-40 \ , 30min \ room \ temperature, 5min \ 100 \ , 30min)$

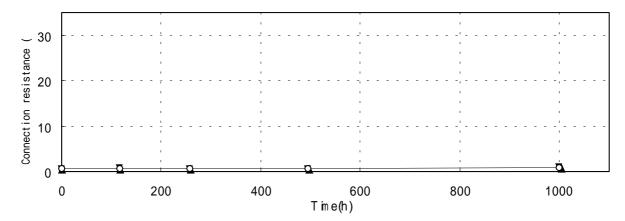


3.3. Changes in connection resistance in a high-temperature, high-humidity test (85, 85%RH)



3.4. Changes in connection resistance in a high-temperature test (100)

3.5. Changes in connection resistance in a low-temperature test (-40)



AC-7206U-18 changes little in connection resistance over time in various tests, thus a stable connection reliability is obtained.

4. Effect of Bonding Temperature on Connection Reliability

-Connection circuits

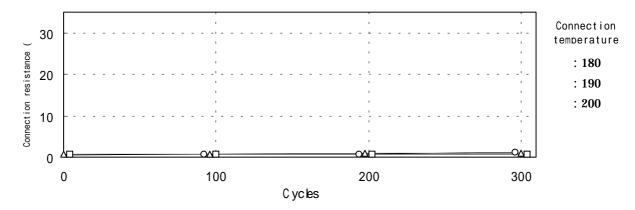
TCP: Pl, 75 μ m; Cu, 18 μ m; Sn plating; pitch, 50 μ m

Glass: ITO sputter; 1 5 / ; electrodes all over

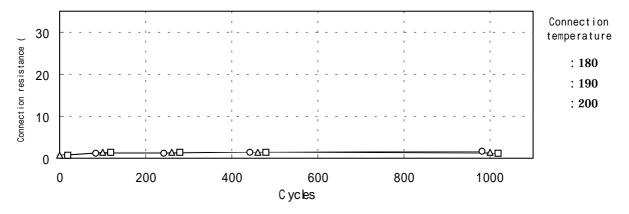
-Bonding conditions; 180,190,200,3MPa,10s; ANISOLM width 1.5mm

4.1. Changes in connection resistance in a thermal shock test

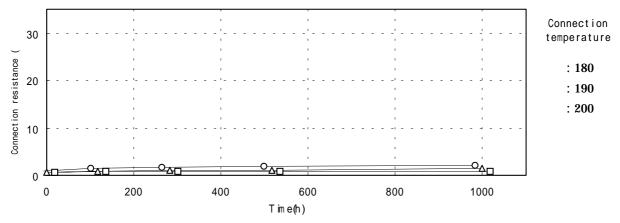
(-40, 30min room temperature, 5min 100, 30min)



4.2. Changes in connection resistance in a high-temperature, high-humidity test (85, 85%RH)



4.3. Changes in connection resistance in a high-temperature, high-humidity test (85, 85%RH)



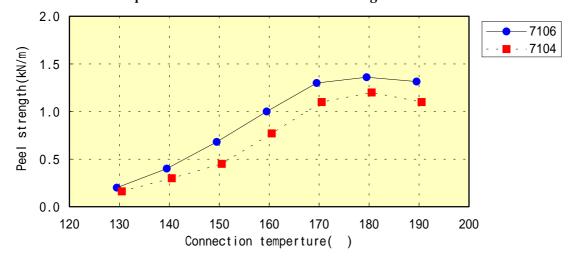
AC-7206U connected at 170 to 200 change little in connection resistance over time, thus a stable connection reliability is obtained.

5. Peel Strength

-Connection circuits

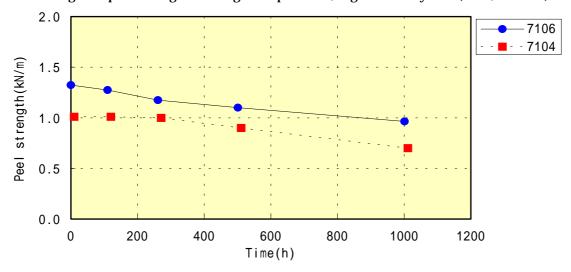
TCP: Pl, 75 μ m; Cu, 18 μ m; Sn plating; pitch, 50 μ m Glass: ITO sputter; 1 5 $\,$ / $\,$;electrodes all over

5.1. Connection Temperature Characteristics of Peel Strength



A high adhesive strength is obtained by bonding at 150 and above.

5.2. Changes in peel strength in a high-temperature, high-humidity test (85, 85%RH)



Our high-temperatature, high-humidity test indicated a considerably small decline in the abhesive Strength of samples, thus showing the high stability of our product.

6. Insulation Reliability

-Connection circuits

FPC: Pl, 125 μ m; Cu, 12 μ m; Ni(2 μ m)/Au(0.1 μ m) plating; pitch, 100 μ m

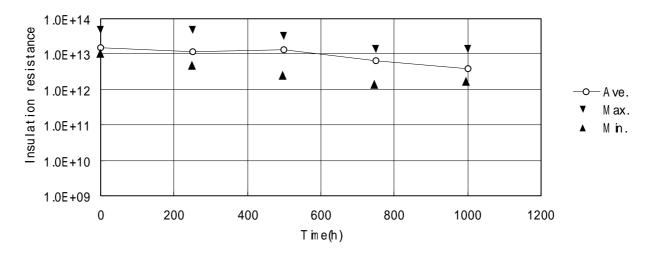
Plate:Insulation glass plate

-Measuring method

Measure the resistance of samples with the condition to 100V DC for 60 seconds.

Measurement condition: 23 and 65%RH

Reliability of test condition: High-temperature, high-humidity test (85, 85%RH)



7. Checking Connection Status

Item	Flatness and contact of conductive particles				
Evaluating equipment	Metallographic, laser, or electron microscope				
Criteria of judgment	All conductive particles should be flat enough.				
Reason	The flatness of conductive particles when connection is established				
	increases the contact area between the particles and electrodes, resulting				
	in a stable conduction and a high connection reliability.				
Method and action	Use an ANISOLM piece of appropriate thickness according to the				
	thickness and line-to-space ratio of the copper foil, and establish				
	connection under appropriate bonding conditions (temperature, pressure,				
	and time)				
Remark	The flatness of conductive particles in connection and a high connection				
	reliability is obtained when the ANISOLM piece between opposite circuits				
	is 3 micrometers thick at the maximum (when measured with a laser				
	microscope, micrometer, or equivalent).				

8 . Physical Properties

ANISOLM	Elastic modules(GPa)	tan max
	40	()
AC-7206U	1.2	125

-Measuring conditions $DVE: hardened\ specimens\ (170\quad ,2min);\ tensile\ mode$ Frequency, 10Hz; programming rate, 10 /min.